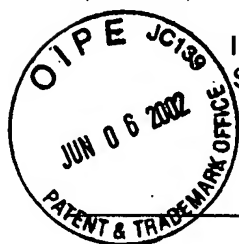


FORM PTO-1449
(MODIFIED)U.S. Department of Commerce
Patent and Trademark OfficeATTY. DOCKET NO.
3167-Z

SERIAL NO.

10/067,372

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Laung-Terng Wang et al

FILING DATE

February 7, 2002

GROUP

2859

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,349,587	09/1994	Nadeau-Dostie et al	714	729	
	5,680,543	10/1997	Bhawmik	714	30	
	6,070,260	05/2000	Buch et al	714	731	
	6,195,776	02/2001	Ruiz et al	714	738	
	6,327,684	12/2001	Nadeau-Dostie et al	714	731	

RECEIVED

JUL 05 2002

Technology Center 2100

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

G. Hetherington et al, "Logic BIST for Large Industrial Designs: Real Issues and Case Studies", Proc., IEEE International Test Conference, Paper No. 142, 1999, pages 358-367.

EXAMINER

DATE CONSIDERED

7/12/2004

EXAMINER: Initial citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. Department of Commerce
Patent and Trademark Office

SERIAL NO. 90/067.372

(Use several sheets if necessary)

Laung-Terng Wang et al

GROUP CEN 8
2859

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

G. Hetherington et al, "Logic BIST for Large Industrial Designs: Real Issues and Case Studies", Proc., IEEE International Test Conference, Paper No. 142, 1999, pages 358-367.

RECEIVED

JUL 11 2002

~~Technology Center 2100~~

EXAMINER

DATE CONSIDERED
7/12/2004

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.